



Optical Characterization and Metrology Equipment List

DESCRIPTION	MANUFACTURER	MODEL #	TYPES OF MEASUREMENTS
Laser interferometer, 6-inch beam diameter (633nm)	Zygo	Dynafiz Verifire	Inspection of optical components, optical surface accuracy, etc. Performance of optical assemblies, lens centering, image resolution, wavefront error, etc.
Lens centering machine	TriOptics	OptiCentric MOT 100	
Lens position measurement	Fogale	Lenscan LS600-1CH	
Lens image analyzer for MTF testing (Modulation Transfer Function)	Optikos	VideoMTF System	
High-resolution wavefront sensor, VIS-NIR (400-1100nm)	Phasics	SID4 HR GE	
Dual-band wavefront sensor, MWIR & LWIR (3-5 μ m and 8-14 μ m)	Phasics	SID4 DWIR	
Focometer (546nm)	Moller-Wedel	MELOS 500	
Electronic autocollimator	Newport	LDS-Vector	Angle between optical surfaces
Autocollimator	Moller-Wedel	AKR 300/40/17.7 SWL	
Goniometer	Moller-Wedel	n/a	
Theodolite	Swisstek	Kern E2	
Coordinate Measurement Machine (CMM), with touch probe	Mitutoyo	Bright VC 200 (BRT-710)	3D inspection or alignment
Portable CMM, with touch probe or laser scanner	Hexagon	Romer Absolute Arm 7312	

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Spectrophotometer, UV-Vis-NIR (200-2500nm)	Agilent	Cary 7000 UMS	Spectral transmittance or reflectance of optical components, thin-film coatings, and various materials
Spectrophotometer, UV-Vis-NIR (200-3000nm)	Perkin Elmer	Lambda 950	
Spectrometer, FTIR (2-330µm)	Bruker	Vertex 70	
Fiber optics spectrometer (200-1100nm)	Ocean Optics	HR4000	LED and light source characterization
Spectroradiometer & photometer (380-780nm)	Photo Research	PR-680 SpectraDuo	
Spectroradiometer (350-2000nm)	ASD	FieldSpec 3	Photometry, radiometry, colorimetry
Photometer & radiometer	International Light	ILT2500	
Laser beam profiler, CCD camera-based (190-1550nm)	Ophir-Spiricon	SP620U	Laser beam characterization
Laser beam profiler, XY scanning-slit (190-1150nm or 650-1800nm)	DataRay	Beam R2	
3D microscope, White Light Interferometer (WLI)	Bruker	NPFLEX	Microscopic inspection and analysis of optical surfaces (roughness and very small features)
Laser scanning confocal microscope	Olympus	LEXT OLS31-SU	
Scanning Electron Microscope (SEM)	Hitachi	S-3400N	
Digital microscope	Keyence	VHX-7000	
Optical microscope	Nikon	n/a	
Stylus profilometer	Bruker	DektakXT	

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